

Notice of References Cited

Application/Control No.

10/594,528

Applicant(s)/Patent Under
Reexamination
YANO ET AL.

Examiner

Sang Nguyen

Art Unit

2886

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0256329	12-2004	Meserol et al.	210/748
*	B	US-2003/0206846	11-2003	Jangbarwala, Juzer	423/241
*	C	US-7,261,816	08-2007	Suzuki et al.	210/282
*	D	US-6,835,295	12-2004	Jangbarwala, Juzer	205/349
*	E	US-6,682,934	01-2004	Jolly et al.	436/73
*	F	US-6,414,182	07-2002	Shingai et al.	560/209
*	G	US-6,086,748	07-2000	Durst et al.	205/775
*	H	US-6,294,073	09-2001	Shirota et al.	205/749
*	I	US-5,624,544	04-1997	Deguchi et al.	205/742
*	J	US-4,908,676	03-1990	Bedell et al.	356/72
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.